Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/625,666	DEGUCHI ET AL.
Examiner	Art Unit
Joon H. Hwang	2166

	SEARCHED				
Class	Subclass	Date	Examiner		
	<u>.</u>				

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Palm See search history printout(s) consulted Jean M. Corrielus consulted Alford Kindred	6/1/2006	JH		